IFW 3752

PATENT APPLICATION

IN THE U.S. PATENT AND TRADEMARK OFFICE

pplicant Hiroshi SEKIYA

Title : LIQUID SPRAY UNIT, METHOD OF SPRAYING

LIQUID USING IT, AND CHEMICAL

Serial No. : 10/522 648 Group: 3752

Confirmation No.: 7545

Filed : September 12, 2005 Examiner: Nguyen

International Application No.: PCT/JP2002/009371
International Filing Date : September 12, 2002

Atty. Docket No.: 4414.P0668US

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

FIRST CLASS MAILING CERTIFICATE

Sir:

I hereby certify that this correspondence is being deposited with the United States Postal Service under 37 CFR 1.8 as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on January 31, 2007.

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Correspondence: Information Disclosure Statement

dated January 31, 2007

including enclosures listed thereon

190.05/05

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THE U.S. PATENT AND TRADEMARK OFFICE January 31, 2007

Application Hiroshi SEKIYA

For: LIQUID SPRAY UNIT, METHOD OF SPRAYING

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INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(e)(1) and 1.98, enclosed herewith is a copy of the European Patent Office Search Report, Form PTO-1449 and the references cited thereon. The relevance of these references is explained on the enclosed search report. Accordingly, further comment at this point in time should not be necessary. Copies of cited U.S. references are not submitted in accordance with 37 CFR 1.98(a).

I hereby certify that each item of information contained in this Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

Further consideration is respectfully solicited.

Respectfully submitted,

TFC/smd

Terryence F. Chapman

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Encl: Copy of European Patent Office Search Report dated December 12, 2006 (3 pages)
Form PTO-1449 and Non-U.S. references cited thereon

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INFORMATION DISCLOSURE 10/522 648 CITATION

🖟: Hiroshi SEKIYA

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Filed: September 12, 2005 Atty. Docket No.: 4414.P0668US Date: January 31, 2007

PATENT DOCUMENTS

Examiner	Cite	Document Number -	Publication Date	Name of Patentee or
Initials*	No.	Kind Code	MM-DD-YYYY	Applicant
	AA	5 413 314	05-09-1995	PLATA et al
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	AK			

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	AO				
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NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AQ	
	AR	
EXAMINER	SIGNA'	TURE DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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